## Notice of References Cited Application/Control No. 10/814,173 Examiner Iriana Cruz Applicant(s)/Patent Under Reexamination WANG ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2003/0123093 A1	07-2003	Hattori, Toshiyuki	358/3.06
	В	US-			
	С	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	-	US-		·	
	7	US-			
	К	US-		,	
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*	-	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP2002027249	01-2002	Japan	Abe Yochito	H04N 1/405
	0	·				
	Р					
	Q					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)							
	U								
	v								
	w								
	x								

A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.